



ELectrical Quality Assurance (ELQA) scope of work and electrical design criteria

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ELQA related presentations:

- ELQA scope of work and electrical design criteria (Tuesday PM WP3/WP7)
- ELQA tests for the HL-LHC IT String (Thursday AM IT String WP16/WP1/WP3/WP6A/WP7/WP9)
- ELQA scope of work for SC links (Thursday PM WP6A/WP7)

2022-09-20 - 12th HL-LHC Collaboration Meeting

Outline



- Introduction to ELQA
- Electrical Design Criteria (EDC)
- Components' lifecycle
- Qualification "building blocks"
- Hardware and software
- Summary



ELQA - introduction



- Test superconducting circuits and magnets (at warm, cold and during thermal transitions)
- Detect non-conformities, signs of faults, ageing, degradation
- The test results are assessed according to defined acceptance thresholds and also they are traced over time to find possible trends and signatures of faults that may develop
- The objective is to validate circuits for thermal cycles and operation at high currents

ELQA has been regularly performed starting from the LHC assembly phase (~2005) until today





Electrical Design Criteria

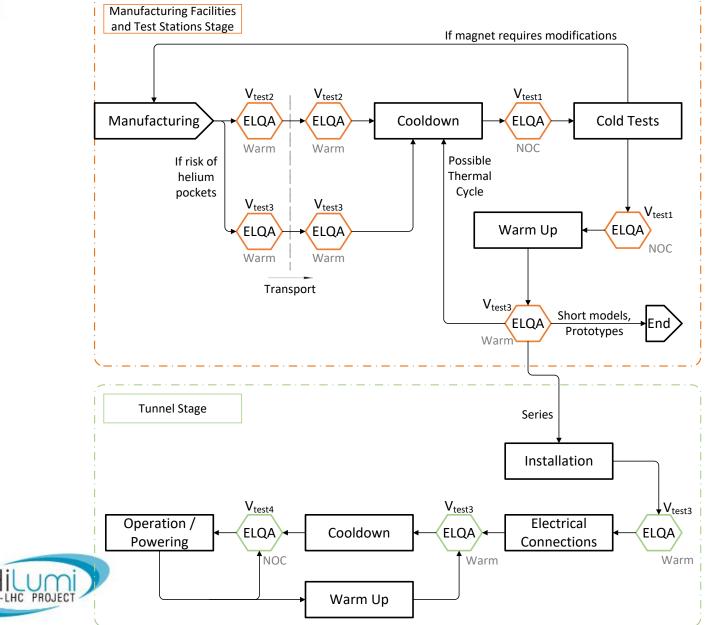


- For each magnet (and cold powering component) an EDC document was created
- Lifecycle is described
- The necessary voltage withstand levels and test levels at various conditions and at various manufacturing stages were defined
- Documents can be found here: <u>https://edms.cern.ch/project/CERN-0000229487</u>
- List of magnet types:
 - MQXF
 - MBXF (D1)
 - MQSXF
 - MC(S,O,D,T)(S)XF
 - MCBXF
 - MBRD (D2)
 - MCBRD





Components' lifecycle

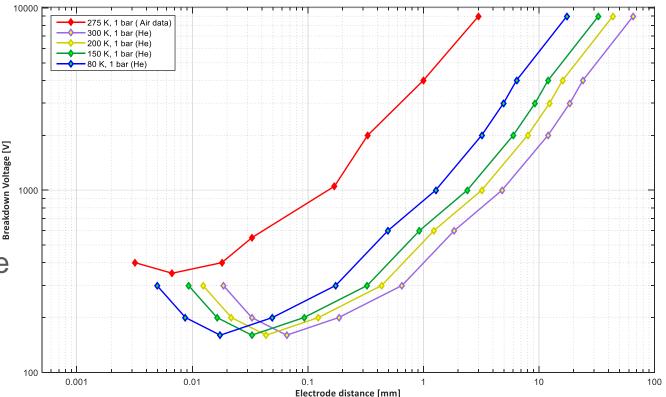


Following the Electrical Design Criteria documents the ELQA tests at an adapted level of voltage need to be performed at multiple stages of a component lifecycle



Helium influence on voltage withstand

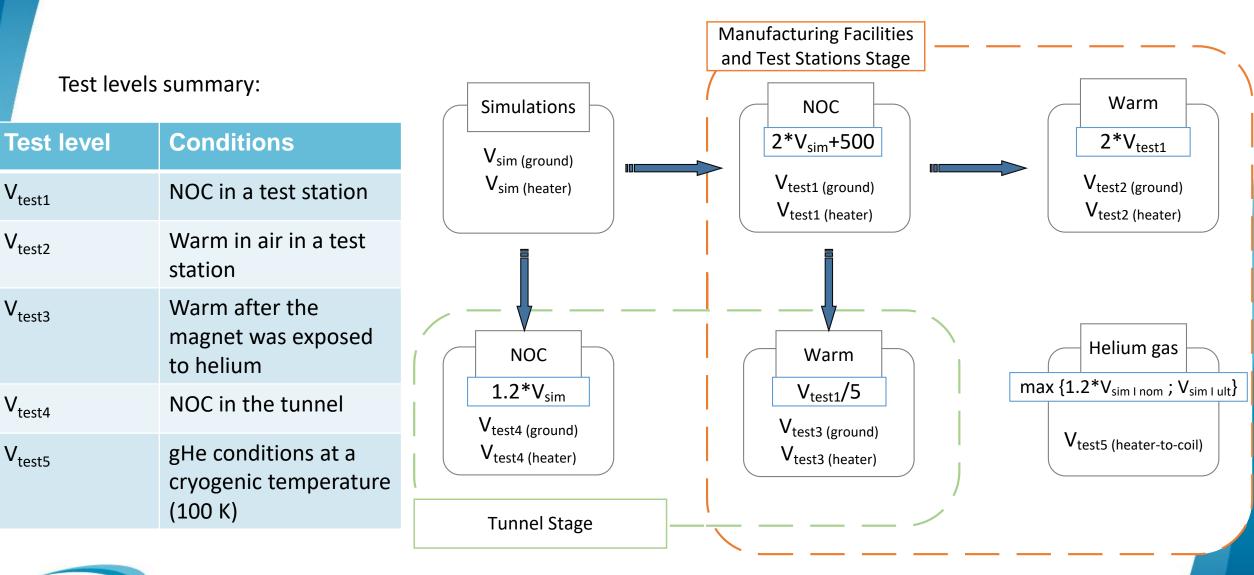
- Voltage withstand of a gap between two bare conductors is given by the medium present in the gap
 - Air
 - GHe at warm
 - GHe at cold
 - LHe
- For gases Paschen law describes the breakdown voltage as a non-linear function of:
 - Pressure
 - Distance
- To perform a comparable HV insulation test of a component in various conditions an approximate scaling factor can be deduced



Liquid helium has a dielectric strength of about 10 kV/mm at T=1.9 K and p=920 mbar



HV test levels definition











- All cold powering components are tested at multiple stages during manufacturing, in test stations, during installation in the tunnel and following thermal cycles in the tunnel
- All test levels are adapted to the worst case realistic scenario that a component may experience
- The test voltage levels are **highest during the initial stages**
 - The objective is to intercept as many faults as possible at an early stage so that the long term stability and smooth operation can be ensured
- Tests at warm require particular attention if the magnet has seen helium
 - Impregnated coils may have enclosed pockets or cracks that vent very slowly
 - Test voltage needs to be scaled down (wrt the test levels at cold) to be compatible with possible gHe
 presence to avoid further degradation of these weaknesses
 - When test voltage is scaled down due to gHe presence, the test result will only be representative if gHe is indeed present
- At the tunnel stage at cold the test voltages give only 20% margin wrt the worst case scenario
 - It is necessary to identify faults that can affect operation
 - It is very hard to replace certain components in the tunnel, especially at cold
 - Minor faults and weaknesses that do not directly affect the operation should not be triggered in this configuration



ELQA is not only HV testing



- Insulation HV tests are one of the main types of qualification
- Multiple complementary tests have to be executed to validate the electrical integrity and to ensure the validity of the HV tests, in particular a conductor must be tested for continuity before the insulation test

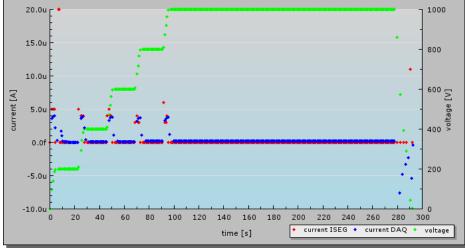
ELQA "building blocks":

- HVQ High Voltage Qualification
- TFM Transfer Function Measurement
- IRC Instrumentation Resistance Check
- ICC Instrumentation Configuration Check
- TDR Time Domain Reflectometry
- COC Continuity of Conductor check
- QHR Quench Heater Resistance measurement
- DVC Diode opening Voltage Check
 - TSQ Temperature Sensor Qualification

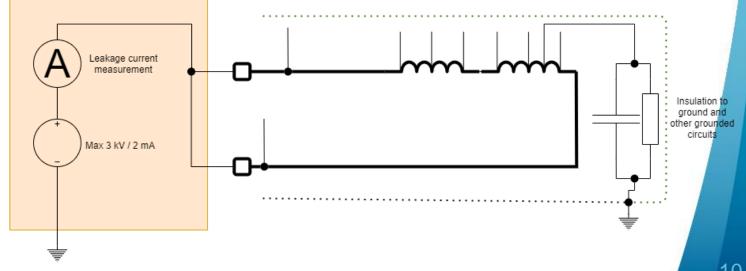


HVQ – High Voltage Qualification

- Each component (circuit, part of a circuit, bus-bar, instrumentation wire, quench heater or cryo heater) is tested individually with respect to ground using a DC voltage source limited to a current of 2 mA
- During the test of a given circuit, all neighbouring circuits (the same electrical safety sub-sector) are grounded
- Applied test voltages are defined for each component at each configuration and for warm and cold tests
- Leakage current is measured, recorded in the central database and compared with predefined thresholds and with values measured on the tested component in the past



HVQ overview





TFM – Transfer Function Measurement

Electrical Qualify Assurance

- During this test the impedance as a function of frequency is measured
- The results of these measurements are used to detect possible circuit anomalies
- The impedance is measured by applying a sinusoidal signal with maximum amplitude of 10 V and maximum current of 1 A
- The frequency range is 0.1 Hz 100 kHz

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EE111-EE113 100 80 60 40 deg. G 1 Hz - 100 kz Max 15 Vp / 1A 20 10 1000 10000 100000 **Principle of TFM measurement** 100 100000 Frequency [Hz] -20 -40 -60 Modulus — Phase 1 Hz - 100 kz Max 15 Vp / 1A

Principle of TFM vs. GND measurement

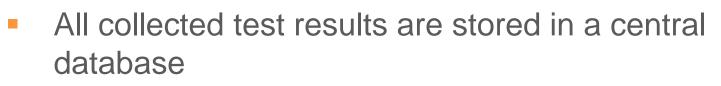


- Other "building block" tests are described in details in the document EDMS 2746933
- All HL-LHC ELQA procedures, hardware and software will be verified in the IT string

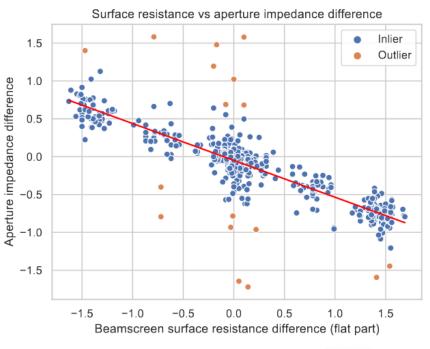


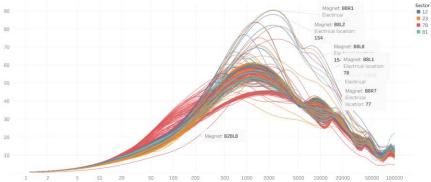
Data analysis





- ELQA at the tunnel stage is repeated periodically: before/after thermal cycles or technical stops
- Trends over time for each measured electrical parameter are evaluated
 - Precursor detection
 - Ageing detection
 - Circuit's health assessment
 - Influence of consolidation works on circuit parameters
- In case of failure of any component in a circuit the ELQA measurements become the reference that can be used for fault localisation

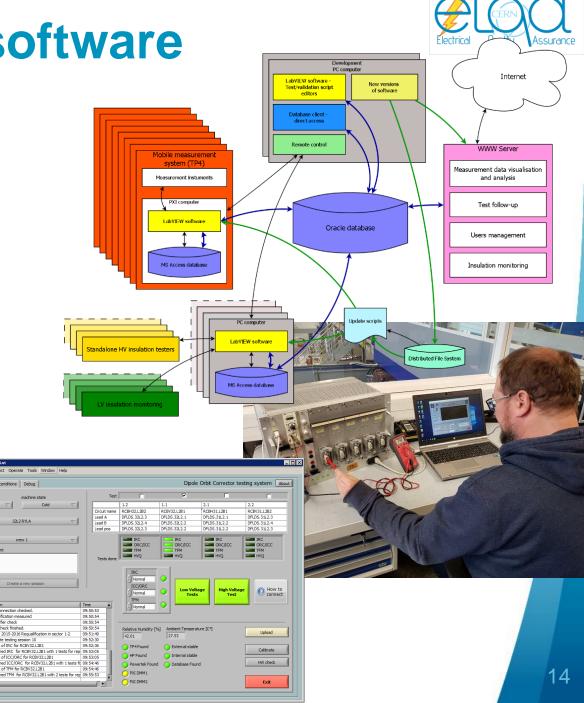






Hardware and software

- The ELQA hardware and software covers all needs for tests of regular LHC circuits and magnets
- Dedicated hardware for qualification of HL-LHC components is being developed
 - New configurations need to be tested
 - New tests will be added
 - Development started
 - Type tests performed
 - Collaboration with HNINP, addendum is being finalised





Summary



- ELQA on HL-LHC superconducting electrical circuits (including the IT string test) will be performed by the ELQA team (TE-MPE-PE)
- For each magnet (and each major cold powering component) an Electrical Design Criteria document was created
 - Components' lifecycle is defined and HV test levels at each stage are defined
- ELQA program is being finalised and the details will be verified in the IT String
- Detailed analysis of acquired data is part of the ELQA
- Dedicated hardware for qualification of HL-LHC components is being developed







